Ref#	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
Lı	102157	((large adj scale adj integration) LSI)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/02/14 11:31
L2	43	l and three adj circuit adj blocks	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/02/14 12:12
L3	832	circuit adj block with (switch switching) with (power supply)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/02/14 12:16
L4	721	circuit adj block with (switch switching) with power	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/02/14 12:15
L5		circuit adj block with (switch switching) with supply	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/02/14 12:15
L6	344	circuit adj block with (switch switching) with (power adj supply)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/02/14 12:16
L7	142	1 and 3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/02/14 13:04
L8	5	power adj supplies with (switch switching) with circuit adj block	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/02/14 13:06
L9	5	second adj power adj supply with (switch switching) with circuit adj block	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/02/14 13:07
SI	41500	LSI	US-PGPUB; USPAT	OR	·ON	2005/02/11 10:16
S2	15614	LSI	ло	OR	ON	2005/02/10 12:43
S3	570	system adj LSI	JPO	OR	ON	2005/02/10 12:43
S4	10	system adj LSI and circuit adj block	ЛО	OR	ON	2005/02/10 13:04
S5	3	system adj large adj scale adj integration	JPO	OR	ON	2005/02/10 13:05
S6	28	system adj large adj scale adj integration	US-PGPUB; USPAT	OR	ON	2005/02/10 13:16
S7	102107	((large adj scale adj integration) LSI)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/02/10 13:17

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S33	205	(324/527).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/02/11 16:51
S34	2700	(324/765).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/02/11 17:11
S35	288	S34 and ((large adj scale adj integration) LSI)	US-PGPUB; USPAT	OR	ON	2005/02/11 16:51
S36	2323	(438/14,17).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/02/11 17:14
S37	231	S36 and ((large adj scale adj integration) LSI)	US-PGPUB; USPAT	OR	ON	2005/02/11 17:15
S38	102107	((large adj scale adj integration) LSI)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/02/11 17:28
\$39	1	S38 and (circuit adj block) with (test adj voltage)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/02/11 17:31
S40	21	S38 and (circuit adj block) with second adj voltage	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON .	2005/02/11 17:40
S41	6	S38 and (circuit adj block) same (simultaneous concurrent) with (test testing tested)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/02/11 17:42
S42	18	S38 and (circuit adj block) same (simultaneously concurrently) with (test testing tested)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/02/11 17:47
S43	0	S38 and (circuit adj block) same selectable adj power adj supply	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/02/11 17:47
S44	3	S38 and (test testing tested) same selectable adj power adj supplies	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON .	2005/02/11 17:49
S45	. 12	S38 and (test testing tested) with (prior before) adj fabrication	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/02/11 17:54
S46	328	S38 and wafer adj test	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/02/11 17:54
S47	3	S38 and wafer adj test with circuit adj block	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/02/14 14:38

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S48	. 1	S38 and wafer adj test with (fabricate fabricated fabrication) with (complete completed completing)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/02/11 17:58
S49	6	S38 and test with (prior before) with (fabricate fabricated fabrication) with (complete completed completing)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/02/11 18:03
S50	0	S38 and common adj external adj terminal with wire adj bonding	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/02/11 18:04
S51	0	S38 and common adj terminal with wire adj bonding	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/02/11 18:04
S52	6	S38 and power near2 terminal with wire adj bonding	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/02/11 18:13
S53		S38 and supply adj terminal with wire adj bonding	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/02/11 18:14
S54	9	S38 and supply adj terminal same wire adj bonding	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/02/11 18:17
S55	31	S38 and third adj circuit adj block	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/02/11 18:17